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| Notice of References Cited | Application/Control No. 10/809,985 | Applicant(s)/Patent Under Reexamination FANG, CHUNG-CHIEH | |
| | Examiner Ed Baird | Art Unit 3693 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| * | A | US-2002/0069155 | 06-2002 | Nafeh et al. | 705/37 |
| * | B | US-6,748,287 | 06-2004 | Hagen et al. | 700/99 |
| * | C | US-4,412,287 | 10-1983 | Braddock, III, Walter D. | 705/37 |
| * | D | US-5,966,312 | 10-1999 | Chen, Vincent Ming Chun | 703/6 |
| * | E | US-2002/0120555 | 08-2002 | Lerner, Julie A. | 705/37 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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